

_ATW2014

15th IEEE Latin-American Test Workshop

Fortaleza, Brazil, March 12th - 15th, 2014



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CALL FOR PAPERS

The IEEE Latin-American Test Workshop (LATW) provides an annual forum for test and fault tolerance professionals and technologists from all over the world and in particular from Latin America to present and discuss various aspects of system, board, and component testing and fault-tolerance with design, manufacturing and field considerations in mind. Presented papers are also published in the IEEE Xplore Digital Library. The best papers of the 15th IEEE LATW will be invited to re-submit to the IEEE Design and Test of Computers, Journal of Electronic Testing: Theory and Applications (JETTA) and the Journal of Low Power Electronics (JOLPE).

Topics of interest include but are not limited to:

- Analog Mixed Signal Test
- Automatic Test Generation
- Built-In Self-Test
- Defect-Based Test
- Design and Synthesis for Testability
- Design for Electromagnetic Compatibility
- Design for Reliable Embedded Software
- Design Verification/Validation
- Economics of Test
- Fault Analysis and Diagnosis
- Fault Modeling and Simulation
- Fault-Tolerance in HW/SW
- Fault-Tolerant Architectures
- Memory Test and Repair
- On-Line Testing
- Process Control and Measurements
- Radiation/EMI
- Hardening Techniques
- Software Fault-Tolerance
- Software On-Line Testing
- System-on-Chip Test
- Test Resource Partitioning
- Yield Optimization

Paper Submission Information:

To encourage and facilitate discussions, participation will be limited. Those interested in presenting recent results at the workshop are invited to submit an extended abstract, one to three pages long, or a full length paper. PDF electronic submissions should be done via the workshop webpage: www.latw.tttc-events.org

Authors should send papers in the IEEE format. Detailed instructions are available at the workshop webpage. The Program Committee also welcomes proposals for panels and special topic sessions.

For additional information, please contact one of the Program Chairs:

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Submission Deadline: November 21st, 2013. Notification of Acceptance: January 5th, 2014.

Camera Ready: January 20th, 2014.

LATW 2014 will take place in Fortaleza. The city is the state capital of Ceará, located in Northeastern corner of Brazil. This makes it the Brazilian state nearest to Europe and North America. With a population close to 2.3 million it is the 5th largest city in Brazil and certainly one of the most vibrant. Located in a state with one of the longest coastlines, the city is surrounded by the waters of the Atlantic Ocean, which provides the city with some of the most beautiful beaches of Brazil. Fortaleza has a beach for every taste: a bohemian beach to stay until the morning, beaches to stroll, for bathing and surfing or for the typical culinary pleasures, offering excellent food and local musical shows. The city will also be one of the host cities of the 2014 FIFA World Cup.

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